

Accelerator laboratory of the Ruđer Bošković Institute

Laboratory for ion beam interactions
Division of experimental physics,
Zagreb, Croatia

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Development: Natko Skukan, Mladen Bogovac,

Postgraduate students: Željko Pastuović, Zdravko Siketić, Marko Karlušić,

Technical: Andrija Gajski, Željko Periša

Others: Hideshi Muto,



History of accelerators at the Ruđer Bošković Institute



1956.
200 keV
neutron generator



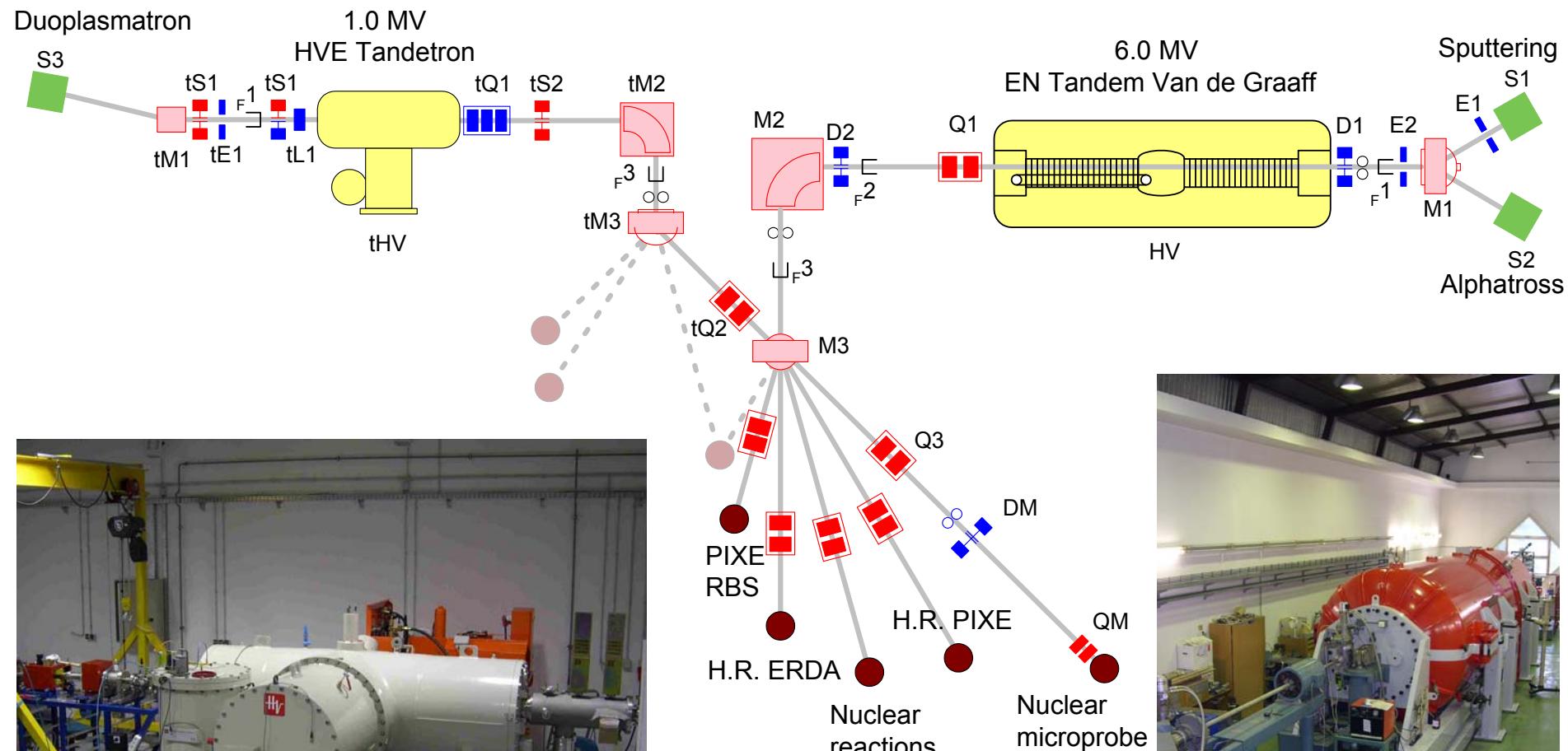
1962.
Cyclotron
(20 MeV deuterons)



1987 Tandem van de Graaff

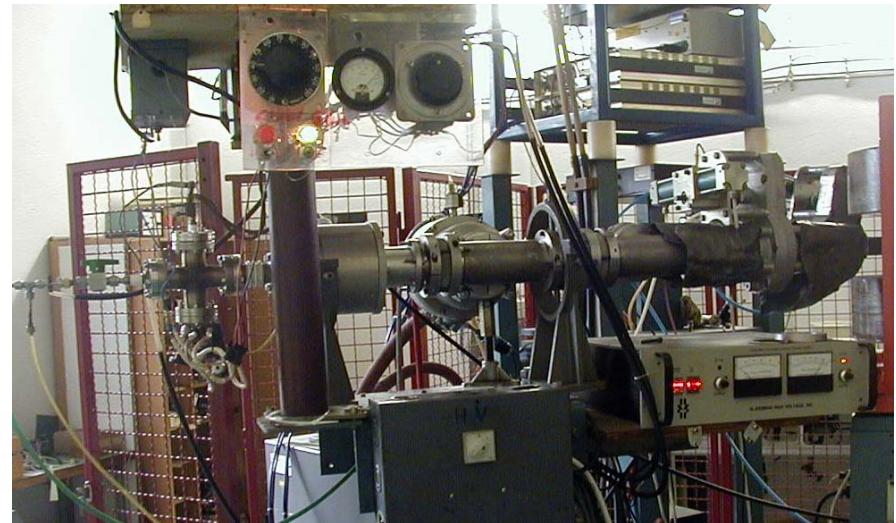


Accelerator laboratory – today



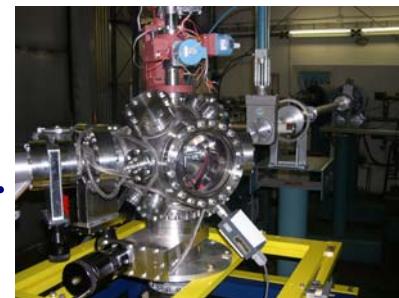
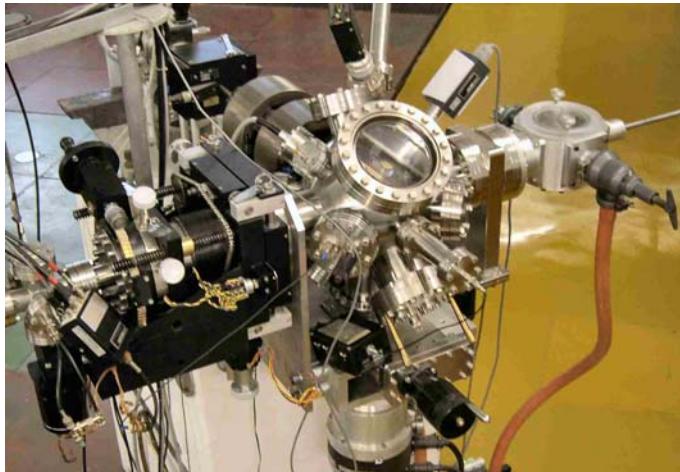
• 6.0 MV EN Tandem Van de Graaff

- 1963 – 1984 Rice University, Houston, Texas
- Since 1987 in routine operation in Zagreb
- Two ion sources – Alphatros (H, He), sputtering (Li, C, O,...)
- Five beam lines



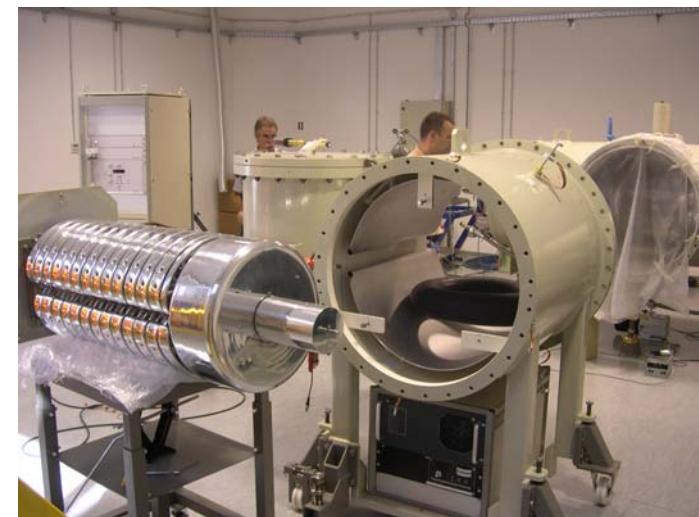
• Beam lines

- Existing beam lines of EN Tandem accelerator
 - 1. IAEA beam line - routine PIXE/RBS
 - 2. TOF ERDA
 - 3. Nuclear reactions chamber
 - 4. High resolution PIXE / ion implant.
 - 5. Nuclear microprobe

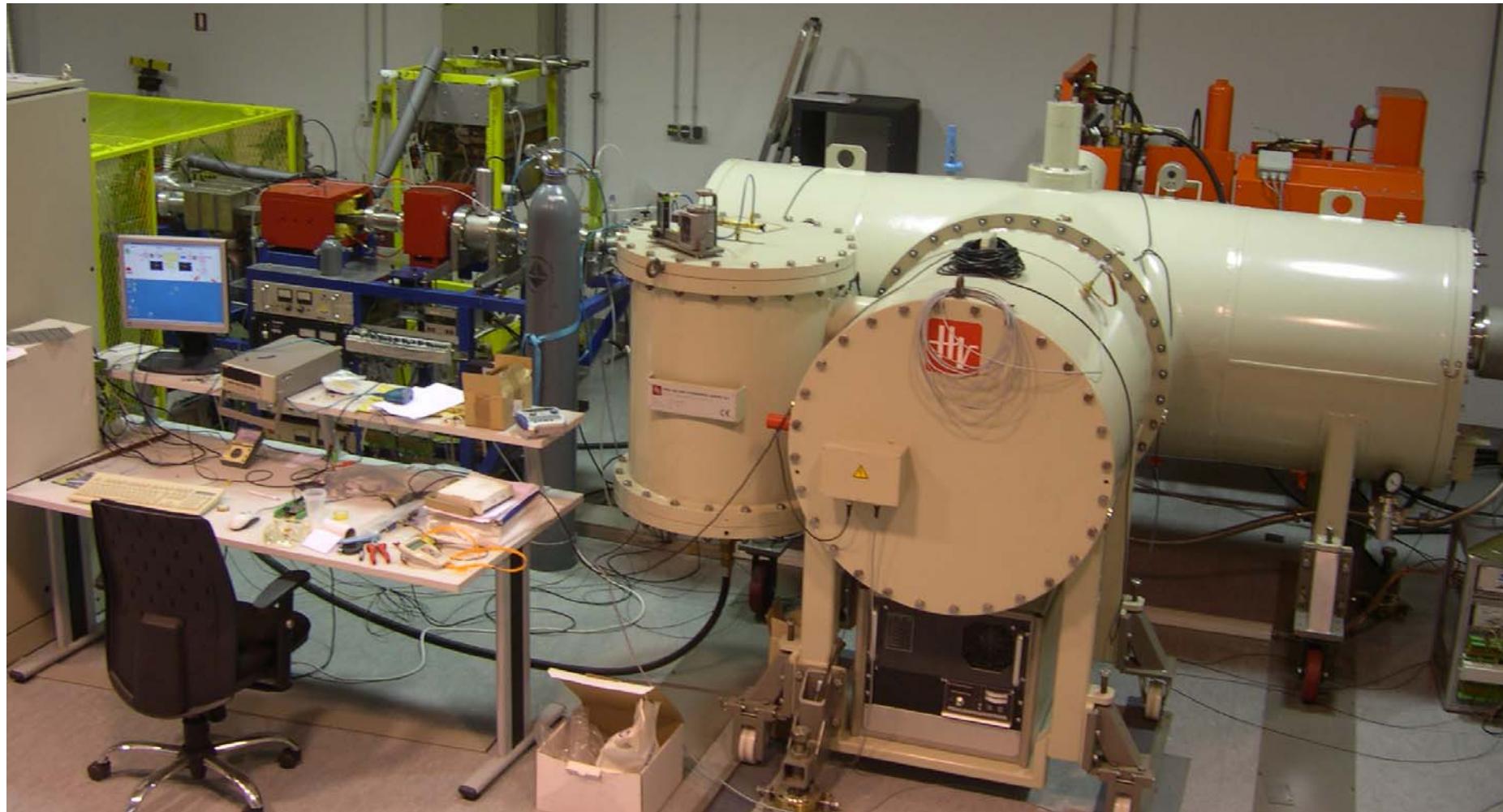


• 1.0 MV Tandetron

- High Voltage Engineering, The Netherlands
(funded by Ministry of science of Croatia and IAEA)
- Direct extraction duoplasmatron ion source
- Sputtering ion source (planned for 2006)
- Terminal voltage range 0.1 – 1.0 MV, high stability,
beam currents up to 50 μA

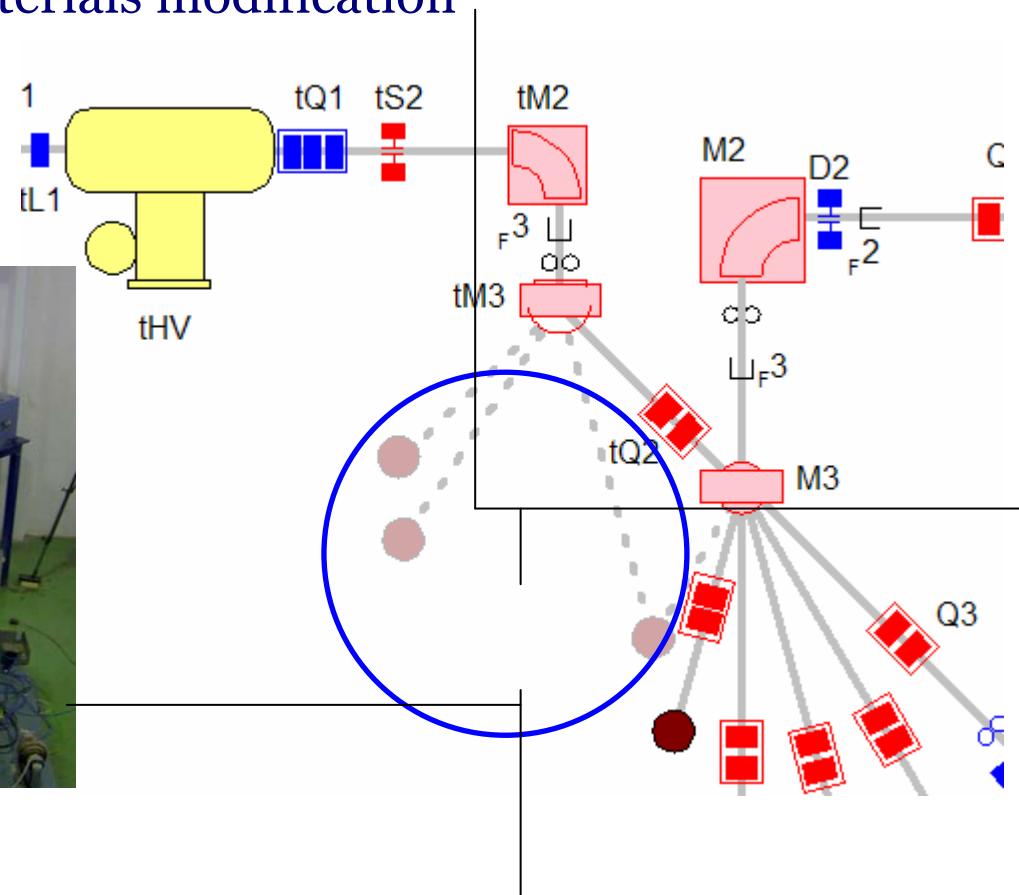


• 1.0 MV Tandetron



• Tandetron beam lines (plans)

- External beam for cultural heritage objects
- New microprobe for heavy ions / low energies
- Two beams chamber for materials modification

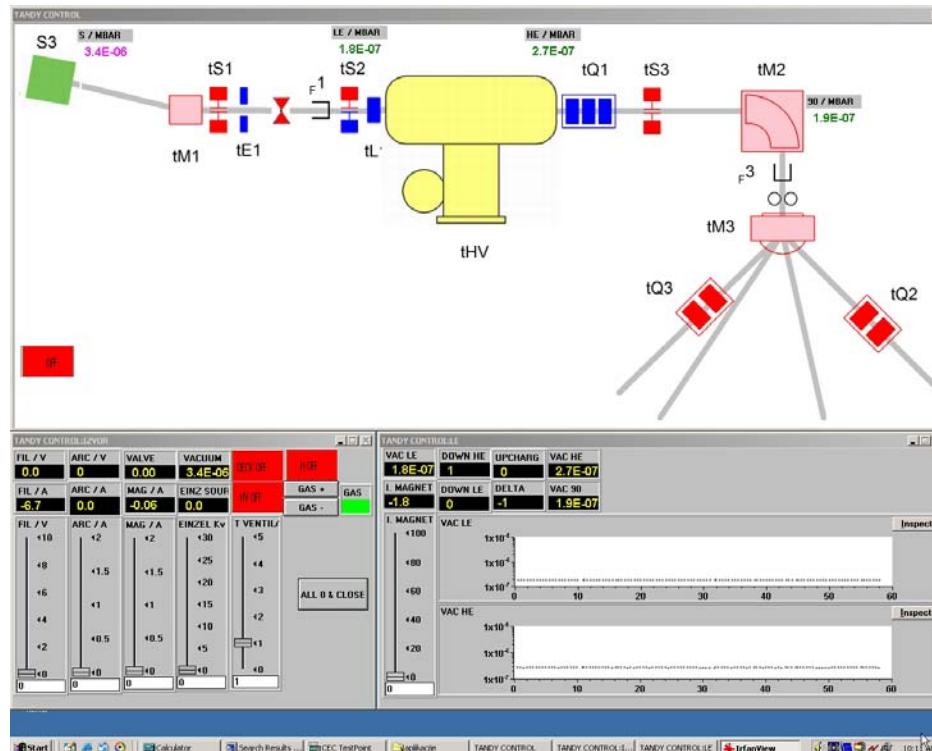


1. New developments

- ACCEL6 & ACCEL1 – accelerator computer control
- Beam optics calculation
- Calculation of electric field distribution
- SPECTOR – data acquisition and sample positioning
- Remote experiments
- New scattering chambers (microprobe and TOF ERDA)



Computer control – ACCEL6 for EN Tandem Van de Graaff and ACCEL1 for Tandetron accelerator



Natko Skukan – IRB
Dejan Đurđenić - Dilogic

- 16 bit AD/DA modules (8 AD, 8DA) (controls for ion sources, accelerator and beam optics system)
- 8 digital inputs, 8 digital outputs
- Controls are based on TESTPOINT

Capabilities:

Remote control (from remote computers)

Reads beam optics parameters from previous experiments

Calculates changes of parameters for change of energy and/or ion

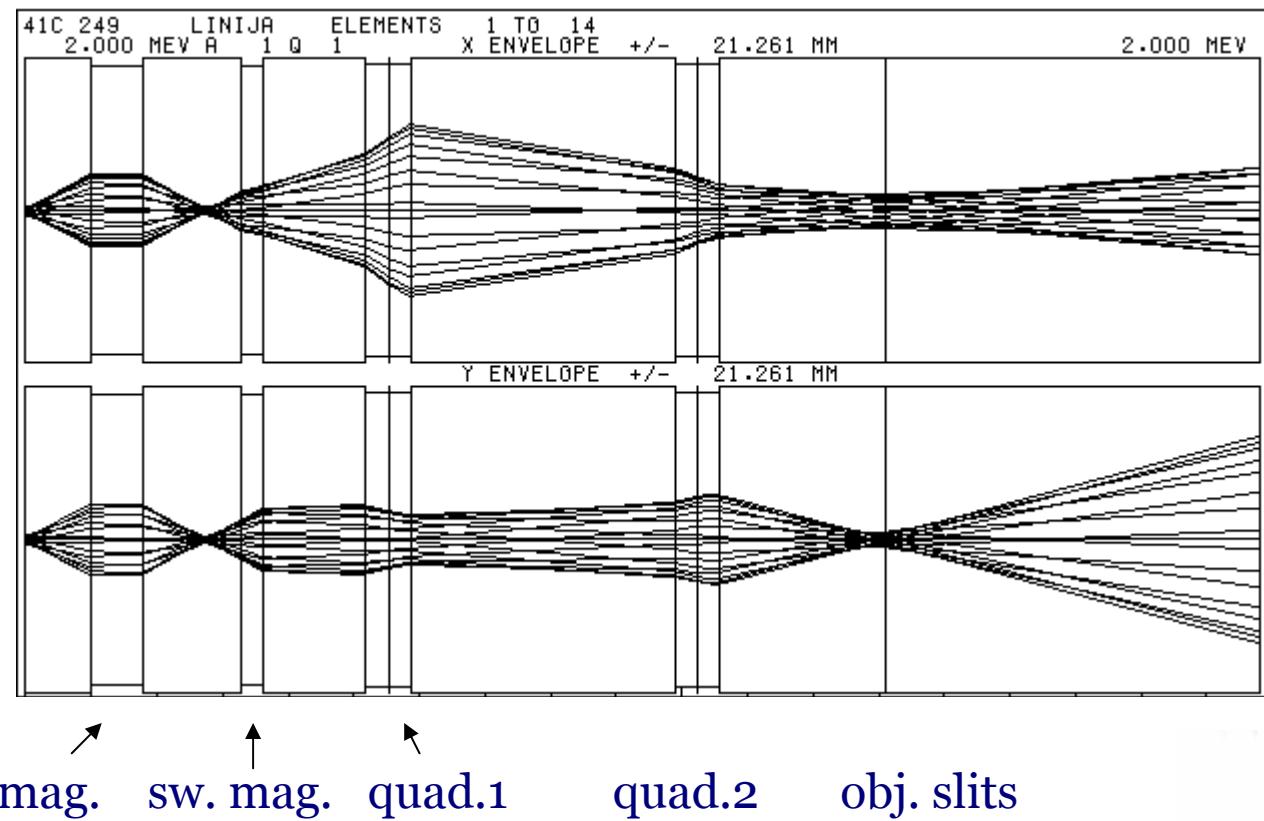
Security interlock system



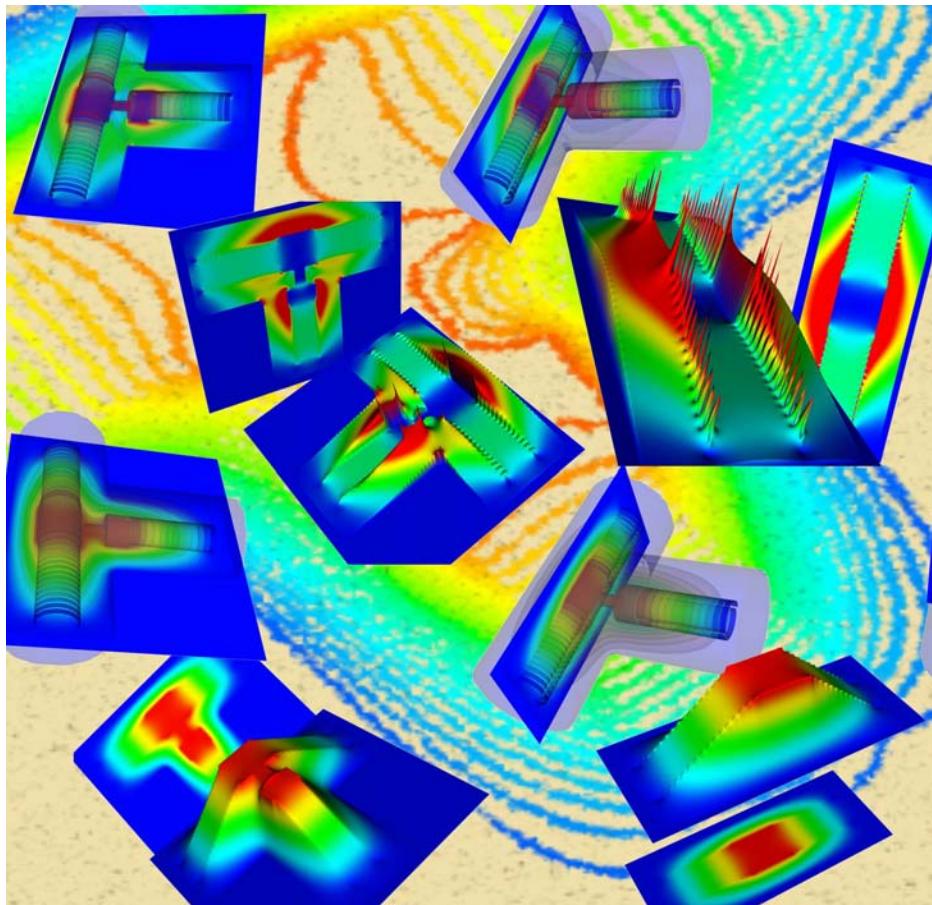
Beam optics calculations – for ion beam from Tandetron to nuclear microprobe

Marko Karlušić

ion beam
from
Tandetron
accelerator



The Robin Hood method – a novel **numerical method** for electrostatic problems based on a non-local charge transfer



P. Lazić, H. Štefančić, H. Abraham
Theoretical Physics Division

Article available on line at:
<http://xxx.lanl.gov/abs/physics/0411192>

Solution of electric field and potential
with 1.0 MV
inside the Tandteron tank

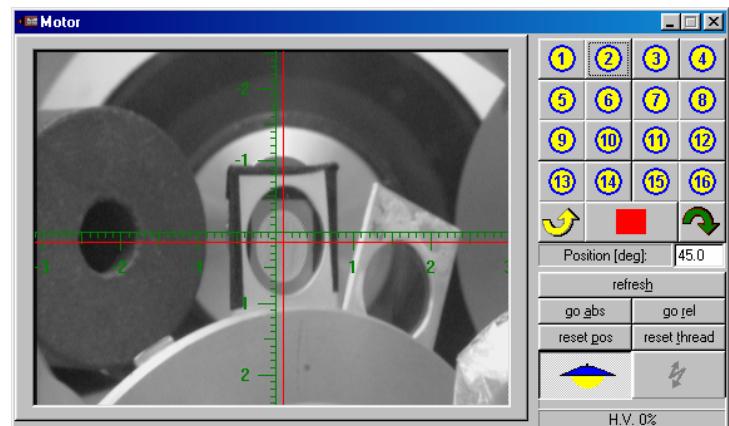
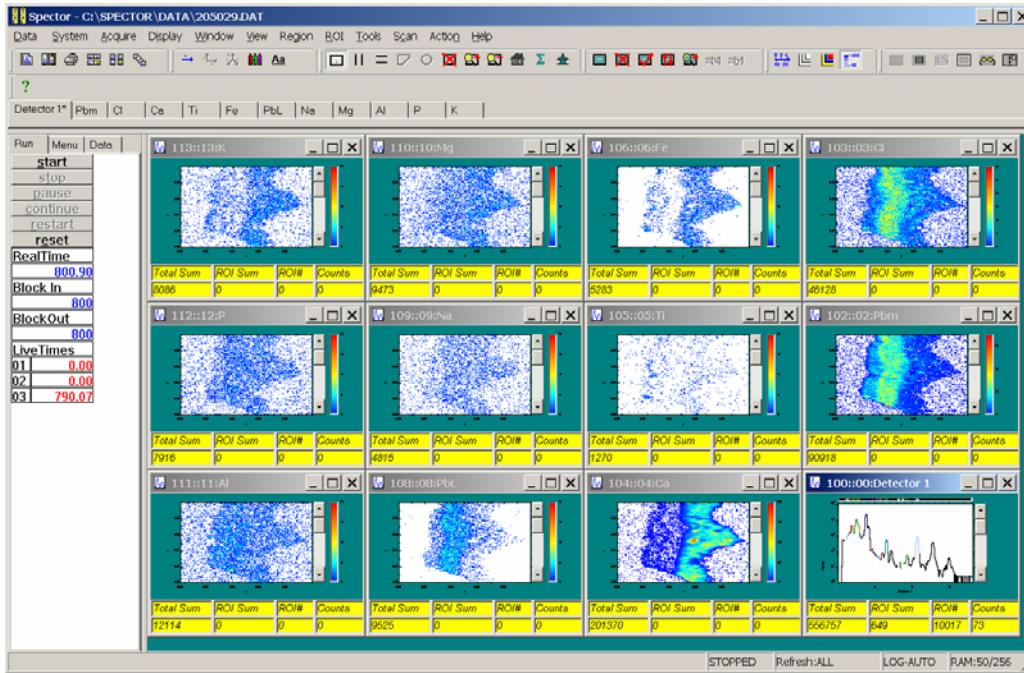


SPECTOR –

Data acquisition /target positioning & beam scanning software



Mladen Bogovac

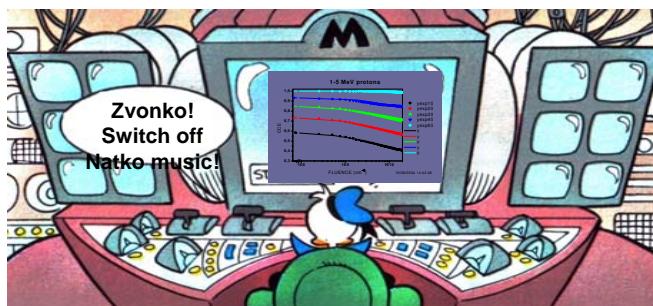
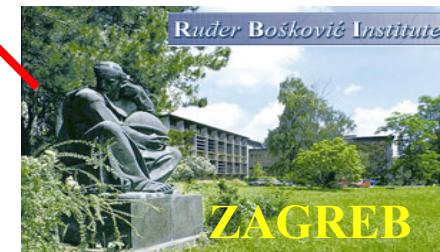


Long distance accelerator experiment –

In collaboration with INFN & Universita di Torino



N. Skukan, M. Bogovac

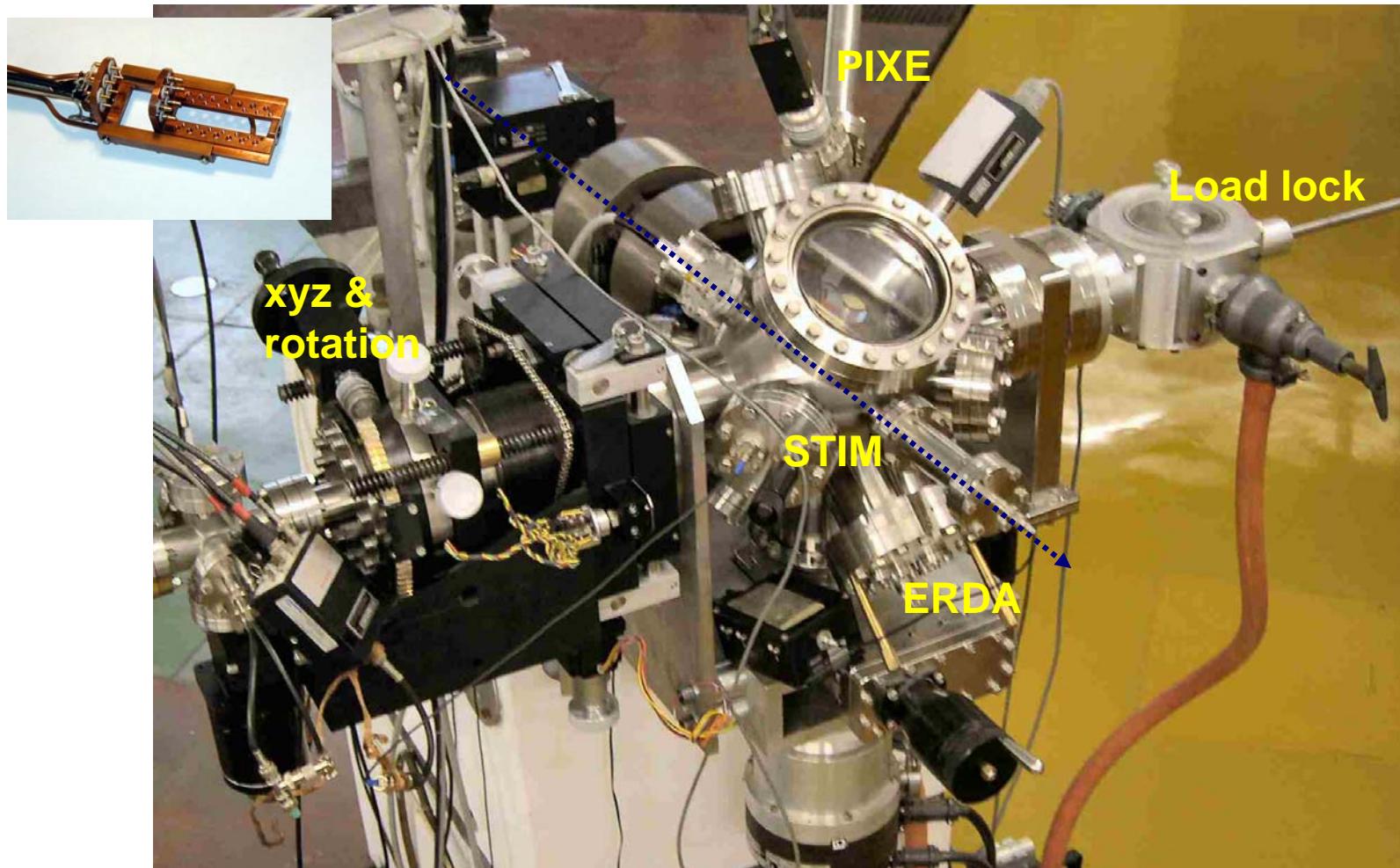


WEB



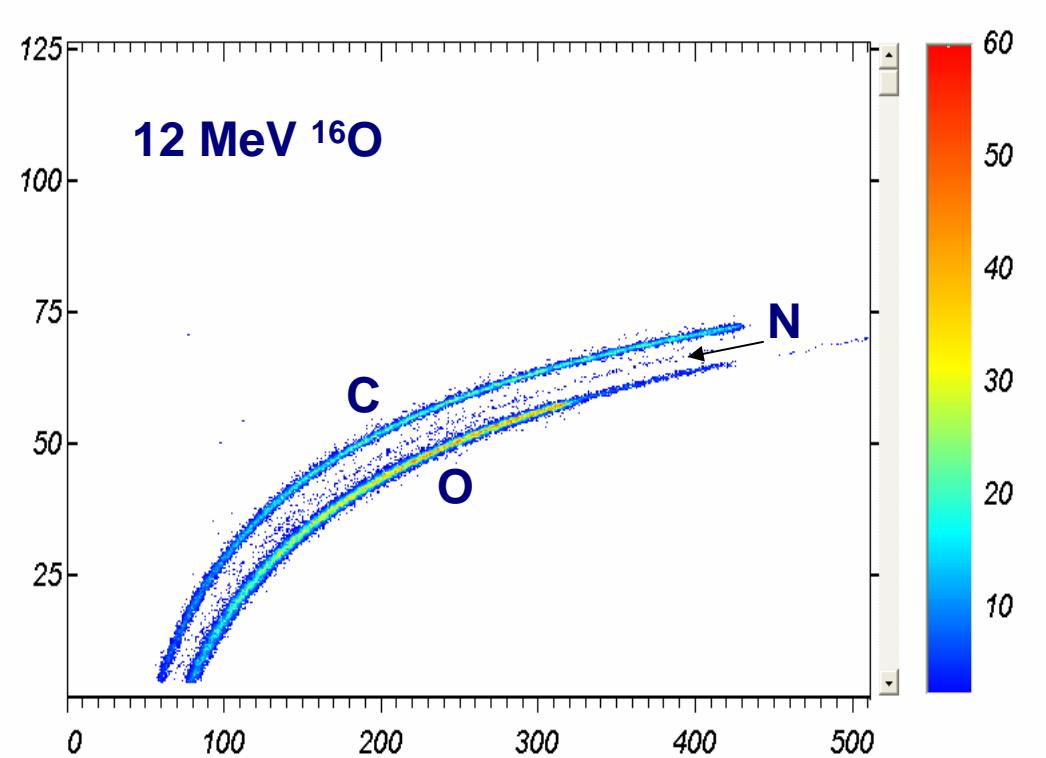
New microprobe scattering chamber

Z. Medunić, M. Jakšić, A. Gajski



TOF ERDA system

Z. Siketić, I. Bogdanović Radović, A. Gajski



Total Sum	ROI Sum	ROI#	Counts	Cursor	Region	Region Sum	
86882	0	10200	0	511 0 (0 2.12121)	0 511 ,511 0, 2 60	86880	

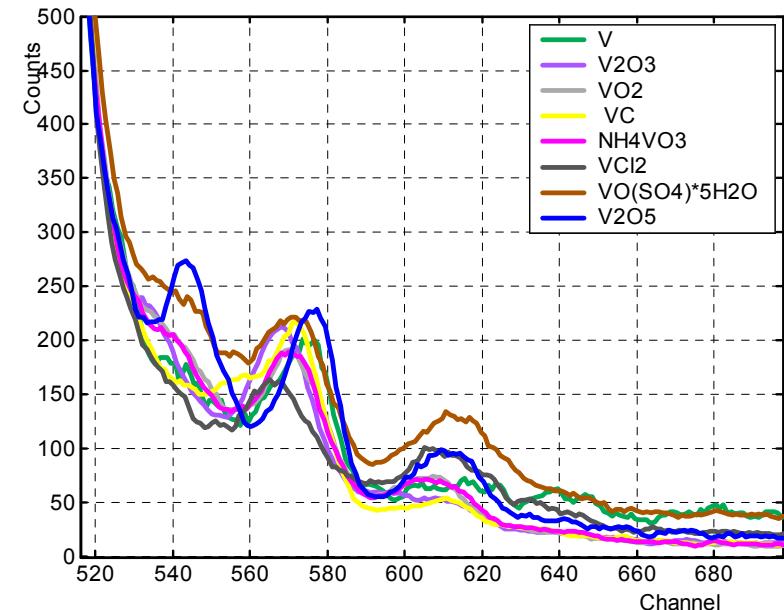
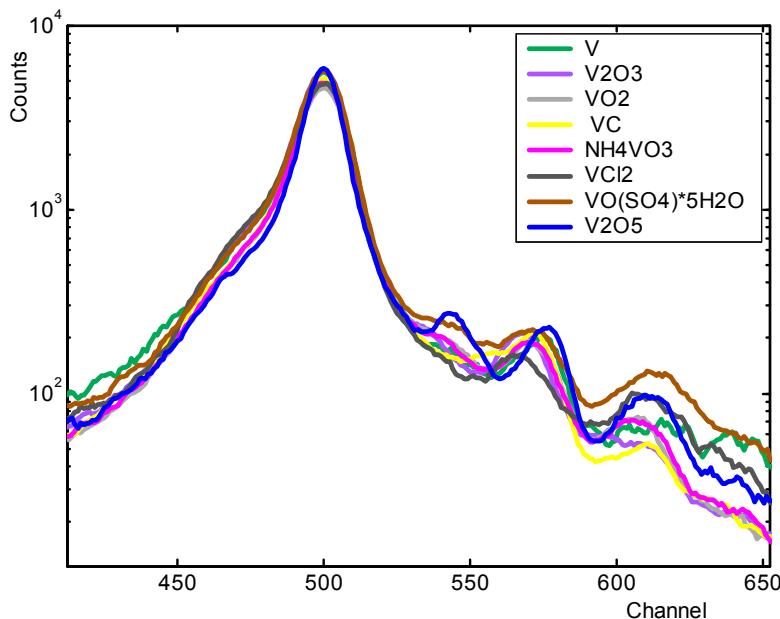
2. Research highlights

- Basic research in nuclear and atomic physics
 1. Light nuclei nuclear reactions
(Laboratory for nuclear reactions - Đ. Miljanić et al)
 2. Inner shell ionisation, chemical effects
 3. Elastic scattering of light ions, data base
- Materials science and applications
 1. Transport of charge carriers – characterisation/modification
 2. Analysis of thin films (RBS &ERDA) with nm depth resolution
 3. Modification of insulators
- Analytical applications
 1. Cultural heritage objects – HRZ
 2. Technological projects (cement, solar cells)
 3. Air pollution monitoring
 4. Other analytical services



• Basic research

- Inner shell ionisation – x-ray spectroscopy
 - ⌚ chemical effects in K β line of Vanadium



• Basic research

- Elastic scattering of light ions
 - ⌚ 2.0 to 6 MeV Li⁷ ion beam on hydrogen

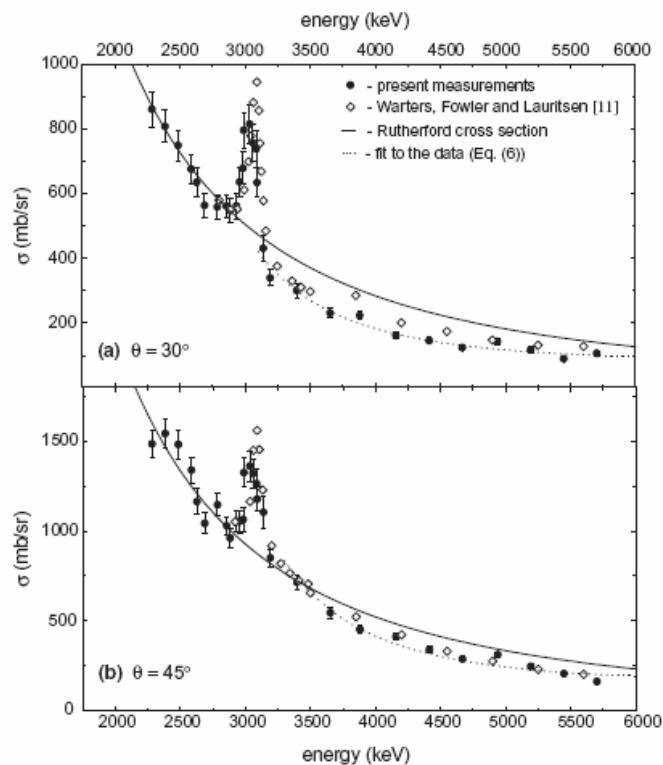
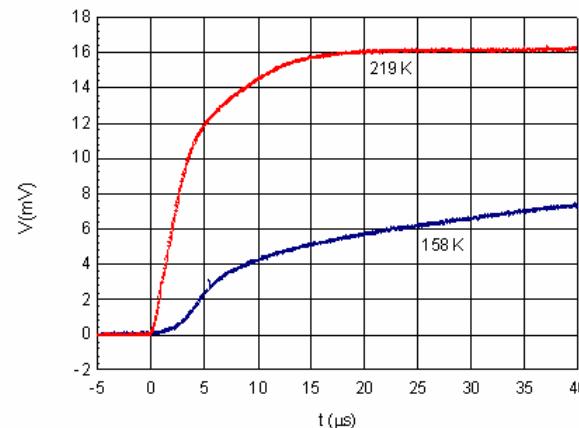
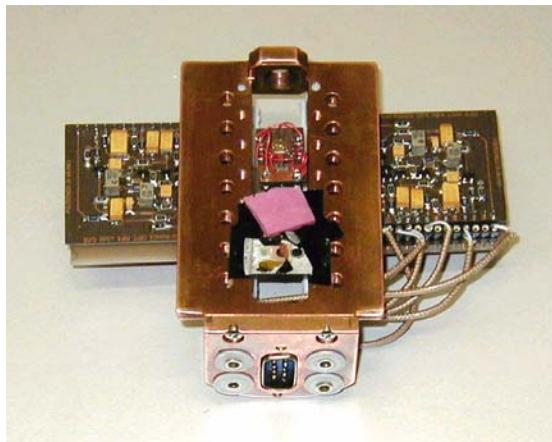


Fig. 2. Energy dependence of the H recoil cross-section (mb/sr) for (a) $\theta = 30^\circ$ and (b) $\theta = 45^\circ$. (●) – present measurements, (◊) – Warters et al. [11]. The solid lines represent the Rutherford cross-sections, and the dotted lines represent fit to the data (Eq. (6)).

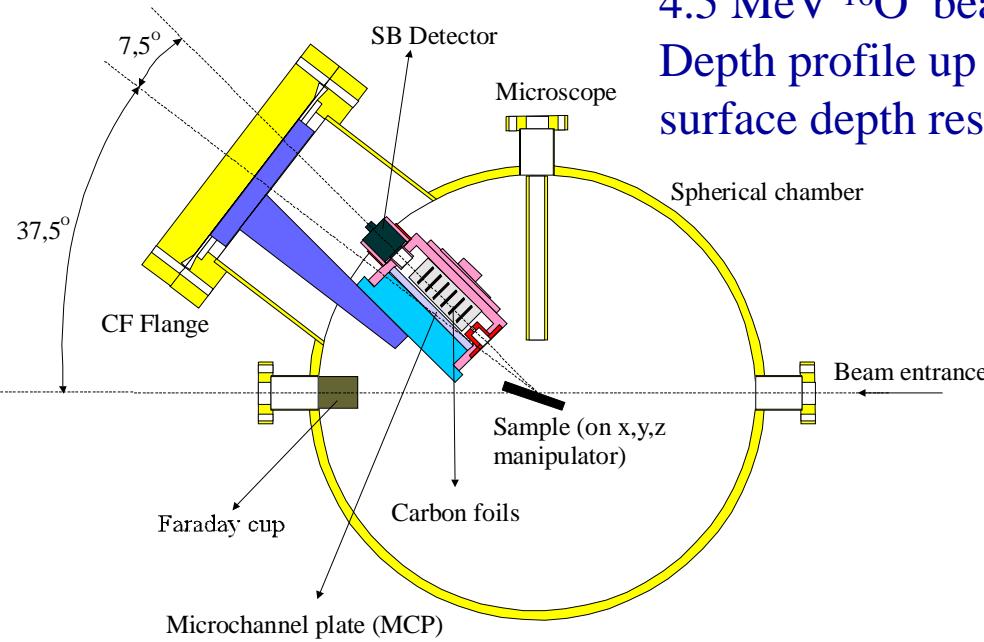


• Materials science

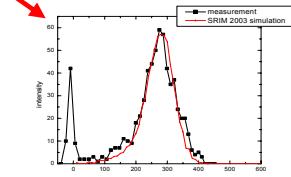
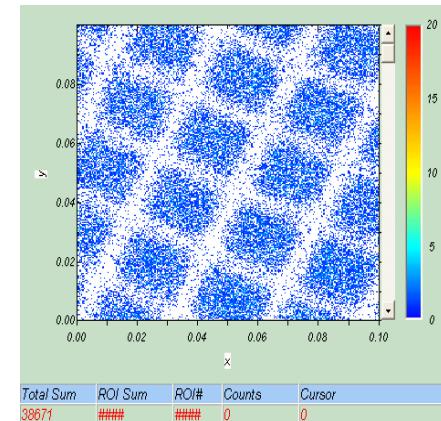
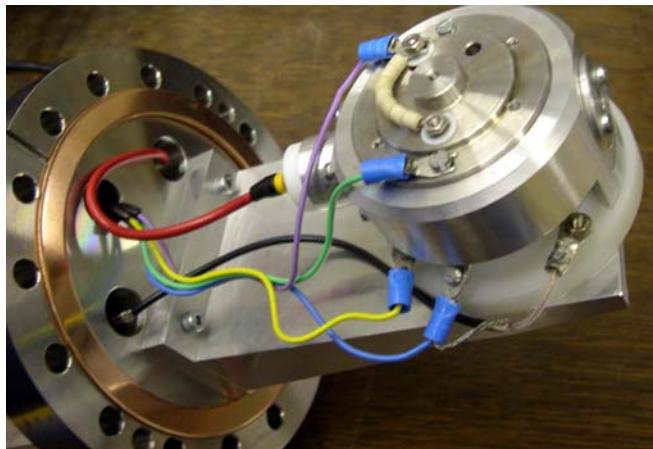
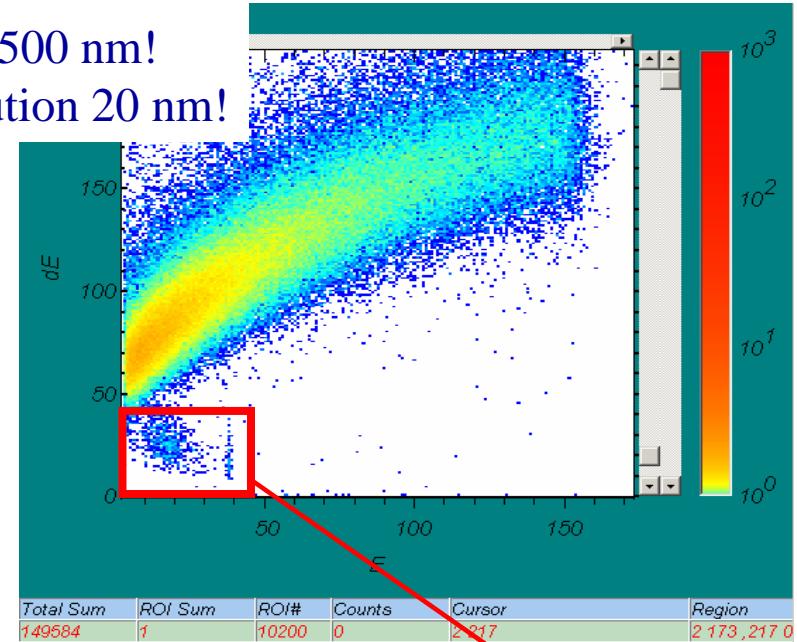
- **Thin film analysis – depth profiling – for nm depth resolution**
 - ⌚ RBS Rutherford backscattering – beam of protons, He, Li, C ions
(nm depth resolution with grazing incidence, or TOF system)
 - ⌚ ERDA - IEE system for H only & 3D on nuclear microprobe (O beam)
 - TOF system for other elements (I, Au beam)
 - ⌚ ion implantation
- **Study of Charge Transport properties** by Time Resolved and Temperature dependent Ion Beam Induced Charge



• Thin film analysis – IEE ERDA for hydrogen



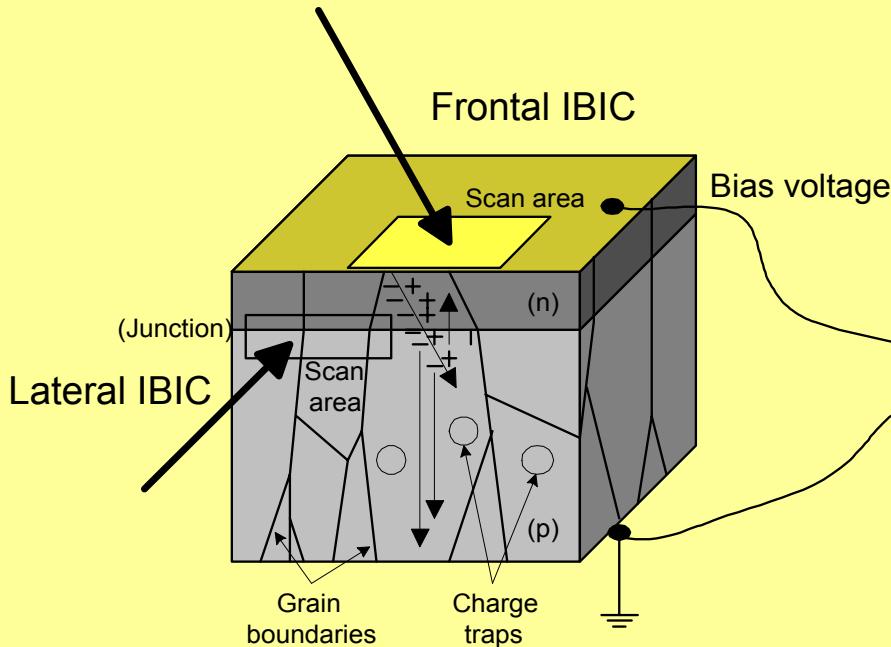
4.5 MeV ^{16}O beam
Depth profile up to 500 nm!
surface depth resolution 20 nm!



2D distribution
of hydrogen
at 300 nm depth
Scan 500 x 500 μm

• Study of Charge Transport properties

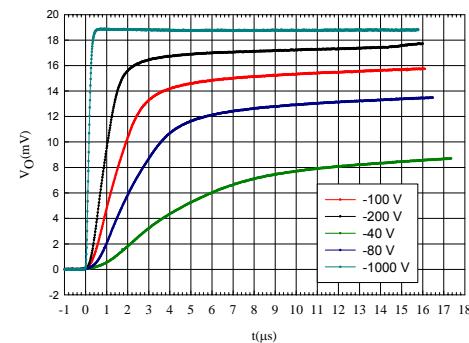
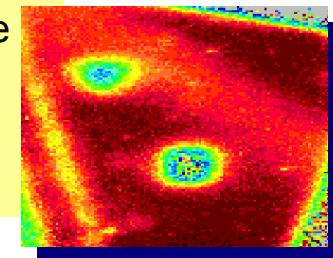
– IBIC technique



Lost Charge

- trapping, detrapping
- recombination (radiative - IL)
- polarisation
- grain boundaries, dislocations, strains,...
- Contacts, dead layers

IBIC pulse



Lateral IBIC

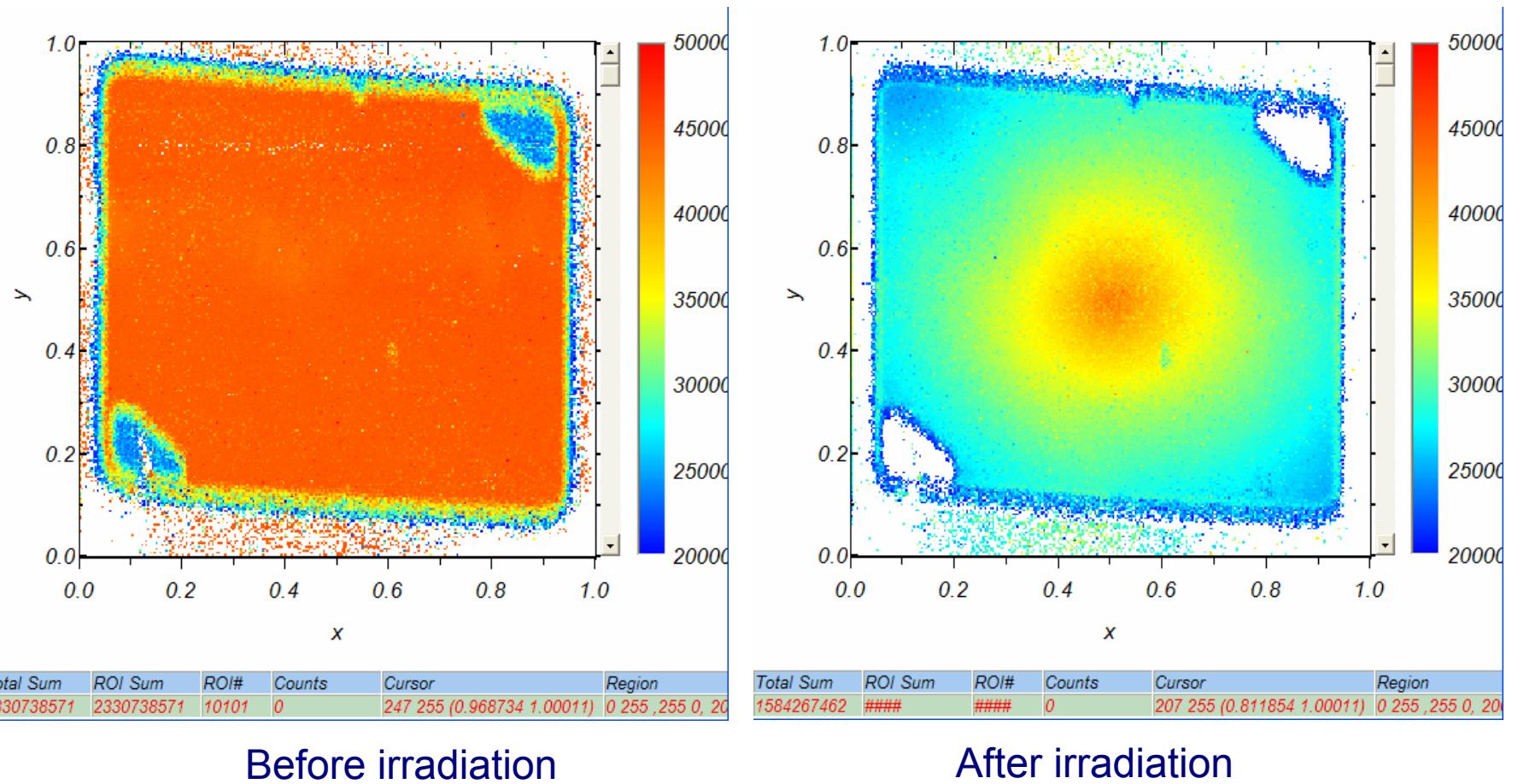
- contribution of both charge carriers
- electric field profile

Frontal IBIC

- short range - surface dead layers
- long range – defects, impurities

Time Resolved IBIC

- IBIC analysis of Si pin diodes
 - ⊕ position dependent radiation damage by 4 MeV O ions

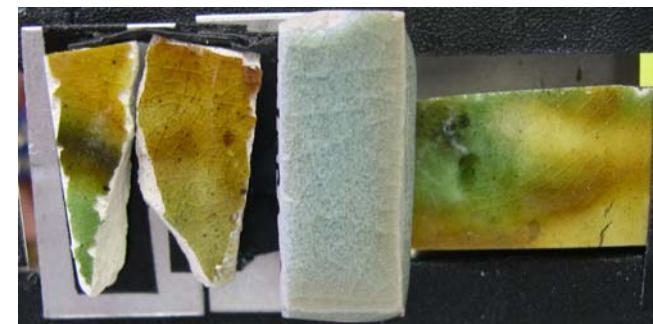


• Applications

Routine analysis will be done in future using Tandetron accelerator !

- Nuclear microprobe PIXE analysis for cultural heritage (IAEA TC project)
 - ☺ St. Marko church portal restoration (with HRZ)
 - ☺ XVII century painter Master HGG (Hans Georg Geiger) SLO/HR cooperation
 - ☺ Chinese porcelain (bilateral project with Beijing)
 - ☺ Other objects (alloys, pigments, ceramics, porcelain, etc)

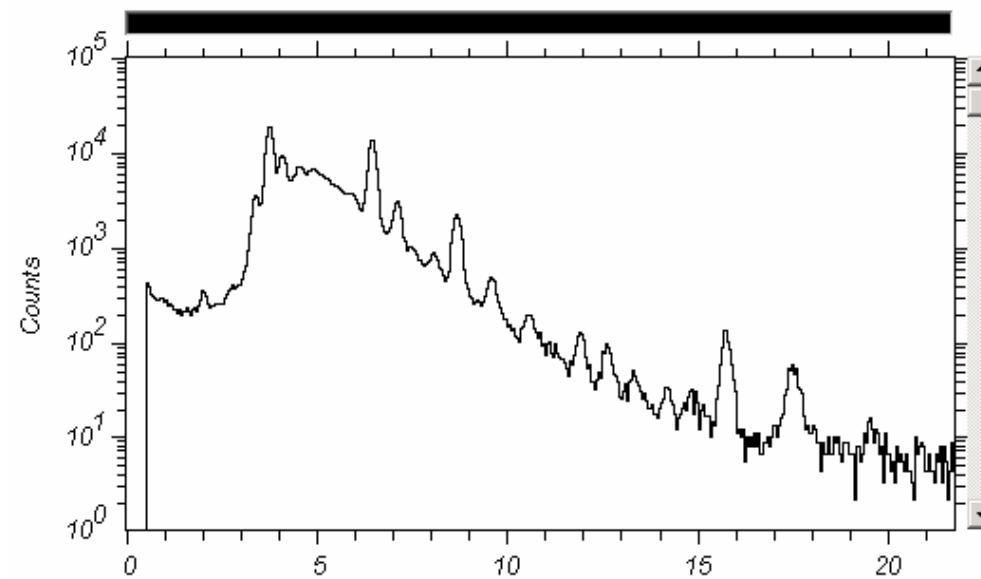
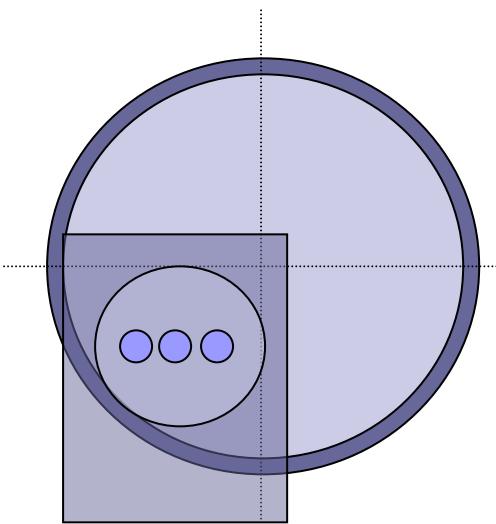
	YELLOW	
	BROWN	
Si	Fe	Cu



• Applications

- Environmental studies – PIXE analysis of air particulates

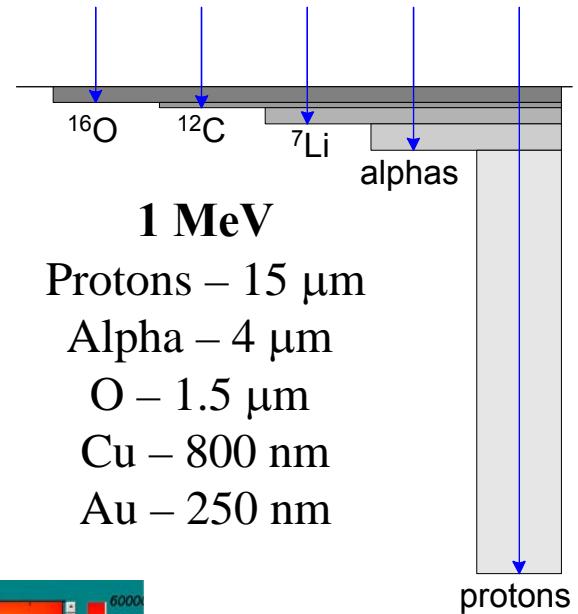
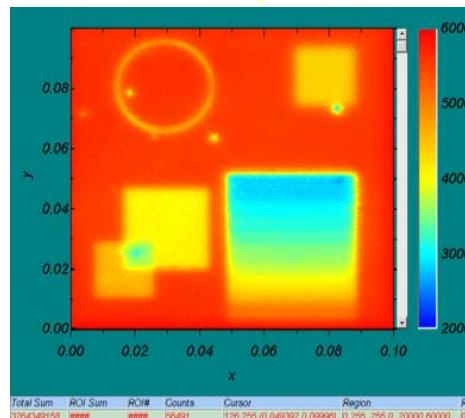
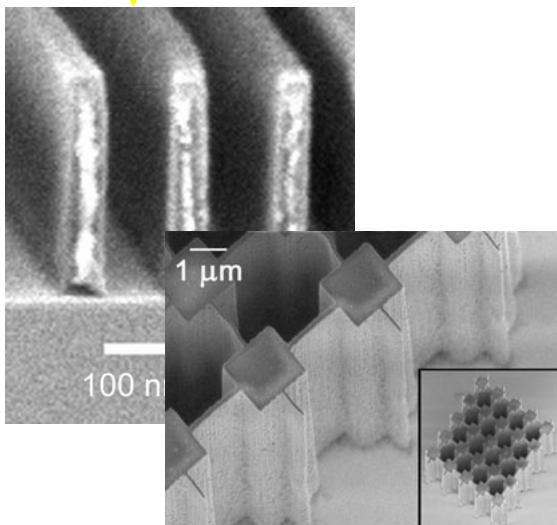
- ☺ for NIST - Certified reference materials – homogeneity tests for candidate CRMs and intercomparisons
- ☺ Collaboration with Institute for Medical Research – national air quality monitoring program
- ☺ Single particle analysis for source recognition



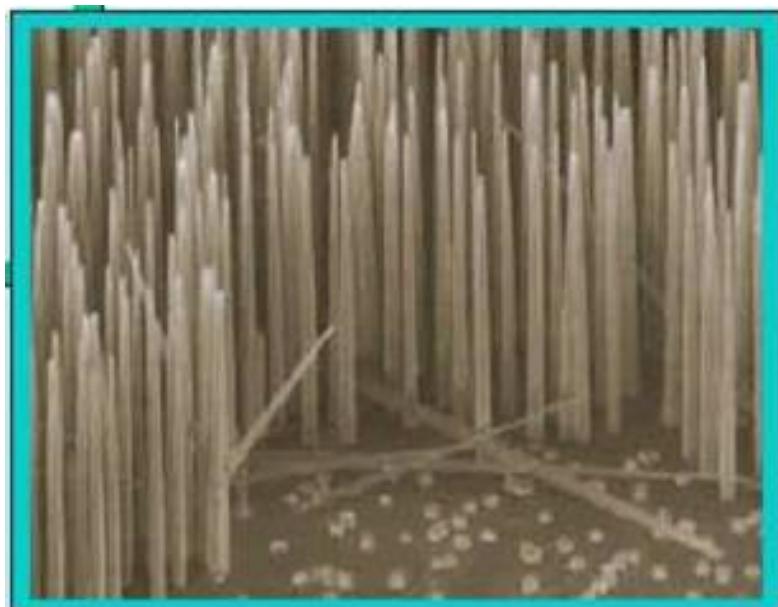
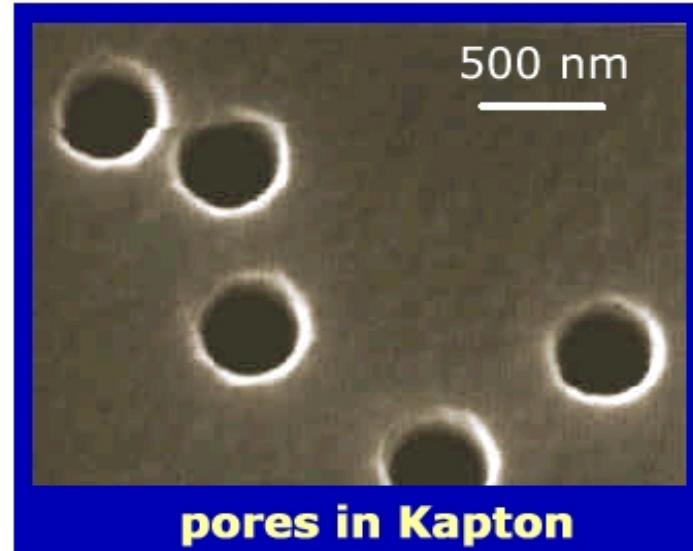
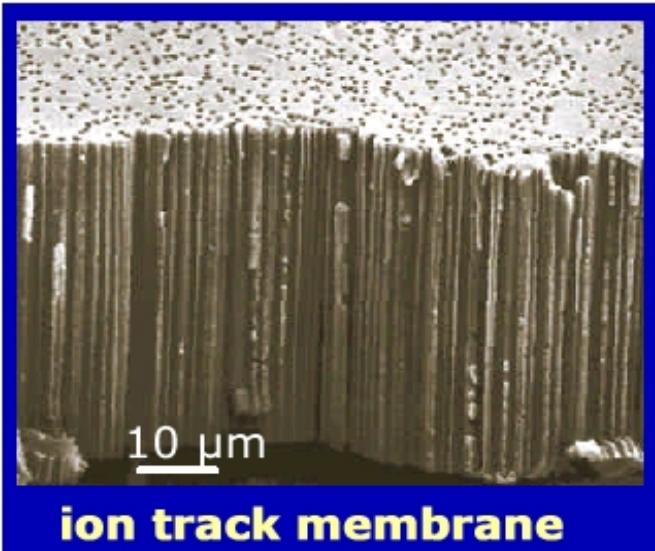
3. New areas

1. Defects

- a. 3D radiation damage structures
 - Lithography
 - Engineering of electronic transport properties
- b. Single ion effects (for high energy loss dE/dx)
 - Membranes, etc

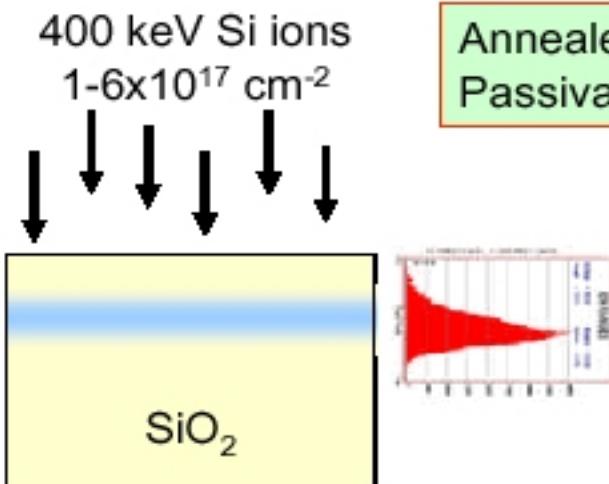
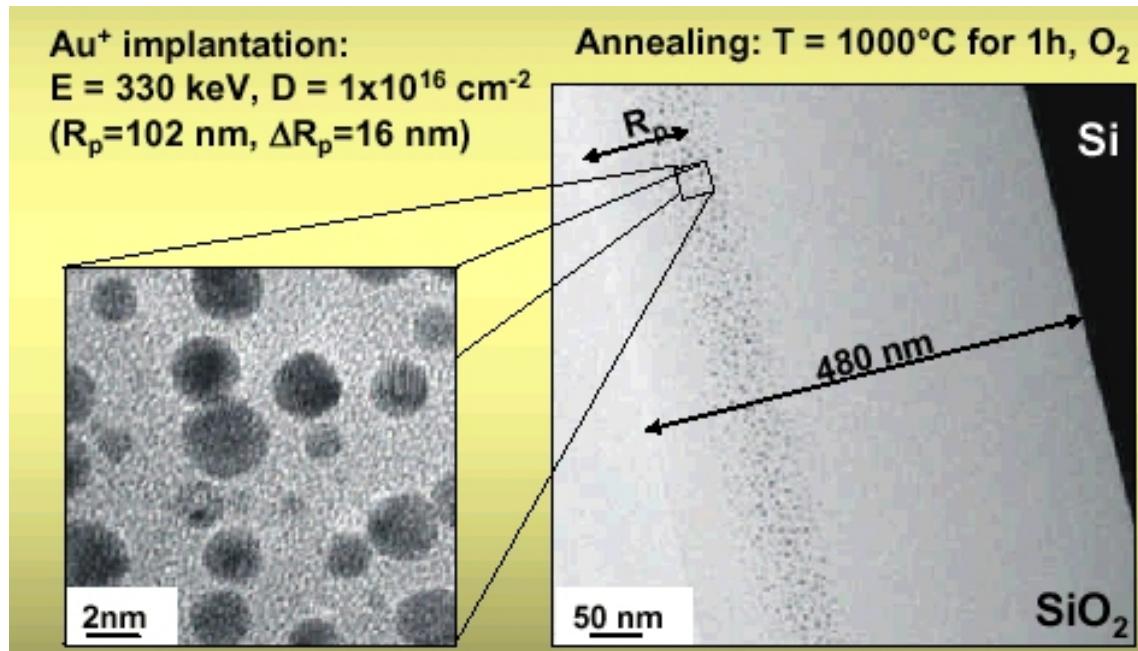


EN tandem:
0.5 – 6 MV
Tandetron:
0.1 – 1 MV

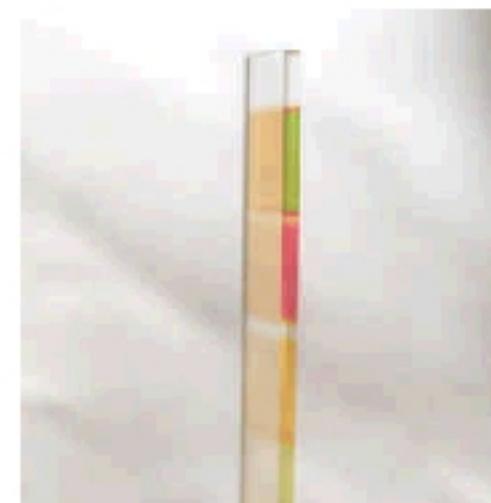


2. Ion Implantation

- IRB – small fluences!
 - but 3D!



Annealed 1100°C in N₂
Passivated 500°C H₂/N₂



- Waveguides formed by 400 keV Si implants:





"Particles, particles, particles."

Thank you!